## Applicant(s)/Patent Under Reexamination Application/Control No. 10/710,843 LIN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2823 Jae Lee **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0248334 A1	12-2004	Hoss et al.	438/039
*	В	US-2005/0218414 A1	10-2005	Ueda et al.	257/094
*	С	US-2006/0175621 A1	08-2006	Ohtsuka et al.	257/088
	۵	US-			
	Е	US-			
	F	US-			
	G	US-			
	H	US-			
	_	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N		·			
	0					
	Р					
	a					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.